

**Notice of References Cited**

Application/Control No.

10/800,827

Applicant(s)/Patent Under  
Reexamination  
CHEN ET AL.

Examiner

Kezhen Shen

Art Unit

2627

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2005/0050100 A1	03-2005	Chin, Yuan-Chang	707/104.1
*	C	US-2004/0252967 A1	12-2004	Sheu et al.	386/046
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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